

## NEWS LETTER

### HSIC USB 3.0 test board ( Breakout Adapter )

Zebax offers High Speed Inter-Chip , HSIC , USB 2.0 and USB 3.0 test board tailored for debugging, development and characterization applications. [ZX230](#) product line offers test board functionality for characterization of USHB 2.0 and USB 3.0 systems, both Host and Cabling systems. “ZX230 Bundle” offers feature reach headers & stuffing option providing best in class module for eye diagram testing, Jitter Analysis DLL, RX Jitter, LFPS TX, LFPS RX analysis as well as USB 2.0 and USB 3.0 Pre- Electrical compliance test. Power measurements can be conducted using the accessible headers.

**Application:** Functional and interface testing of ASIC, Signal characterization, performance analysis., pre-bringup.



### ZX230AP

Introducing [ZX230AP](#), best in class HSIC USB 3.0 ( Backward compatible with USB 2.0 ) test board. Using USB 3.0 **Type A Plug** connector meeting electrical compliance testing—eye diagram, jitter ( random) deterministic, total jitter, SCC profiles tests, Slew Voltage levels and more ). Designed In 4 layers 100  $\Omega$  differential trace impedance meeting HSIC USB 3.0 test board measurement requirements.

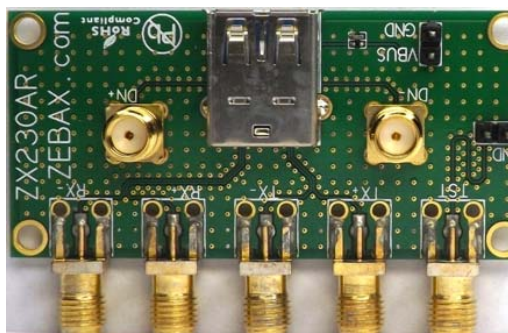
**Application:** Functional and interface testing of ASIC, Signal characterization, performance analysis, pre-bringup, pre-compliance test.



### ZX230AR

Introducing [ZX230AR](#), best in class HSIC USB 3.0 ( Backward compatible with USB 2.0 ) test board. Using USB 3.0 Type A Receptacle ( Socket ) connector meeting electrical compliance testing—eye diagram, jitter ( random) deterministic, total jitter, SCC profiles tests, Slew Voltage levels and more ). Designed In 4 layers 100  $\Omega$  differential trace impedance meeting HSIC USB 3.0 test board measurement requirements.

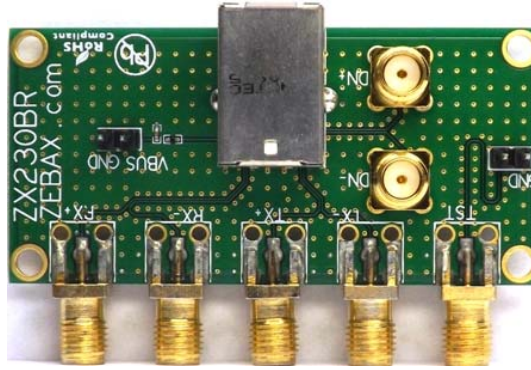
**Application:** Functional and interface testing of ASIC, Signal characterization, performance analysis, pre-bringup, pre-compliance test.



## [ZX230BR](#)

Introducing [ZX230BR](#), best in class HSIC USB 3.0 ( Backward compatible with USB 2.0 ) test board. Using USB 3.0 Type B Receptacle ( Socket ) connector meeting electrical compliance testing—eye diagram, jitter ( random) deterministic, total jitter, SCC profiles tests, Slew Voltage levels and more ). Designed In 4 layers 100  $\Omega$  differential trace impedance meeting HSIC USB 3.0 test board measurement requirements.

**Application:** Functional and interface testing of ASIC, Signal characterization, performance analysis, pre-bringup, pre-compliance test.



## [ZX230ABR](#)

Introducing [ZX230ABR](#), best in class HSIC USB 3.0 ( Backward compatible with USB 2.0 ) test board. Using USB 3.0 Type AB Receptacle ( Socket ) connector meeting electrical compliance testing—eye diagram, jitter ( random) deterministic, total jitter, SCC profiles tests, Slew Voltage levels and more ). Designed In 4 layers 100  $\Omega$  differential trace impedance meeting HSIC USB 3.0 test board measurement requirements.

**Application:** Functional and interface testing of ASIC, Signal characterization, performance analysis, pre-bringup, pre-compliance test.



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